

# Extracting On-Die Terminators

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# Process Motivation

- Issues with “Clip and Extend” recommendations
- “Black box” rules from experiences since 1992 (Zeelan with Quad format)
  - Decompose model consistent with the internal architecture
    - Example: Output and clamps isolated by curvature changes (Nasef, October 1999 IBIS Summit)
  - Extrapolate for continuous slope
    - Outputs above and on-die extractions here
    - Known SPICE MOSFET level slope discontinuity issues
- Extrapolation recommended in IBIS Cookbook

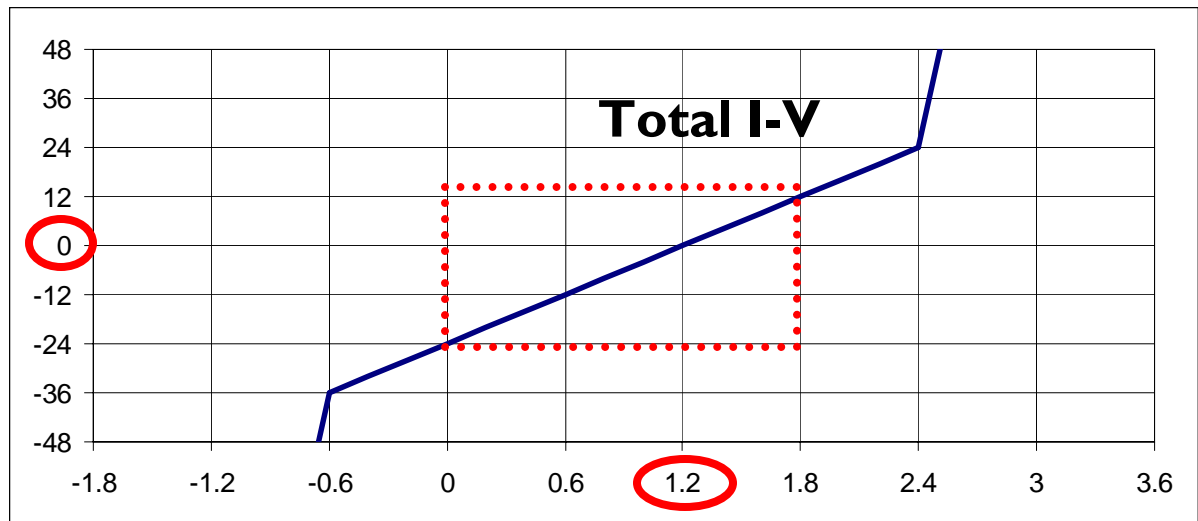
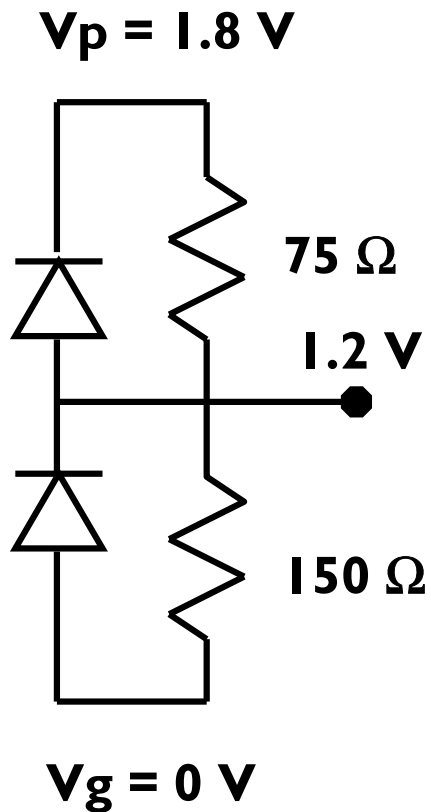


# Creating Clamp Tables

- Goal: Mimic physical device 3-terminal simulation
  - [Gnd Clamp Ref]  $V_g$ , [Power Clamp Ref]  $V_p$  anchors
    - ESD or substrate “diodes”
    - On-Die Terminator (ODT) “resistance” structure
  - Best currents thru  $V_p$  and  $V_g$  for rail analysis
  - I/O node correct with  $V_g$  and  $V_p$  changes
- Default algorithm covers most practical cases
  - Based on deviation from Thevenin resistor ODT
  - “pullup” and “pulldown” ODTs are subsets
  - **DEC: Deviate Extrapolate Calculate**



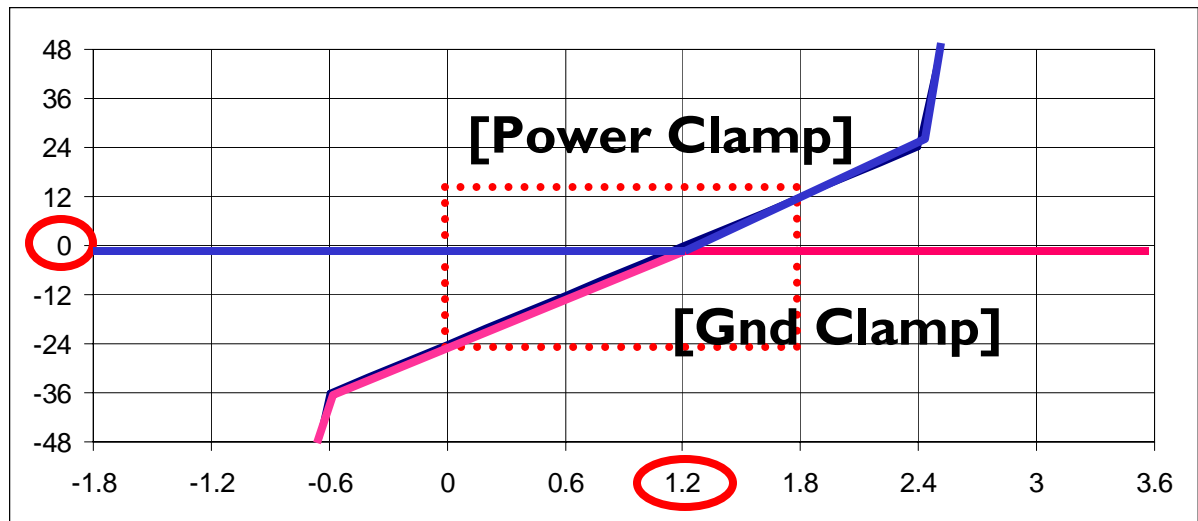
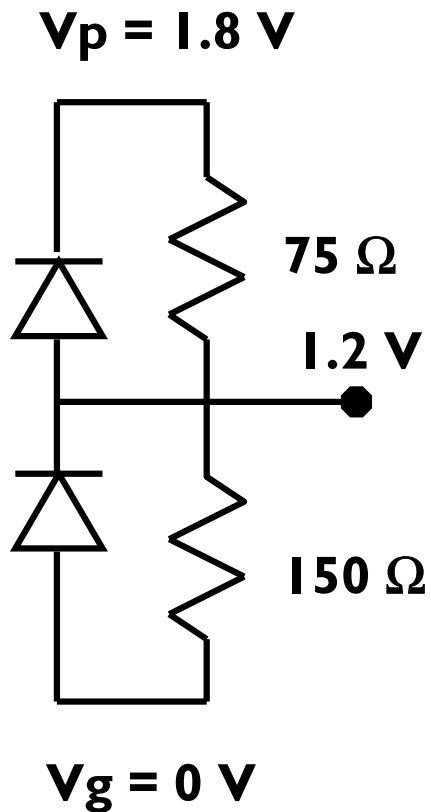
# Example: 50 $\Omega$ , 1.2 V ODT



**50  $\Omega$  Total I-V curve with 0.6 V  
“stick” diodes anchored to each rail**



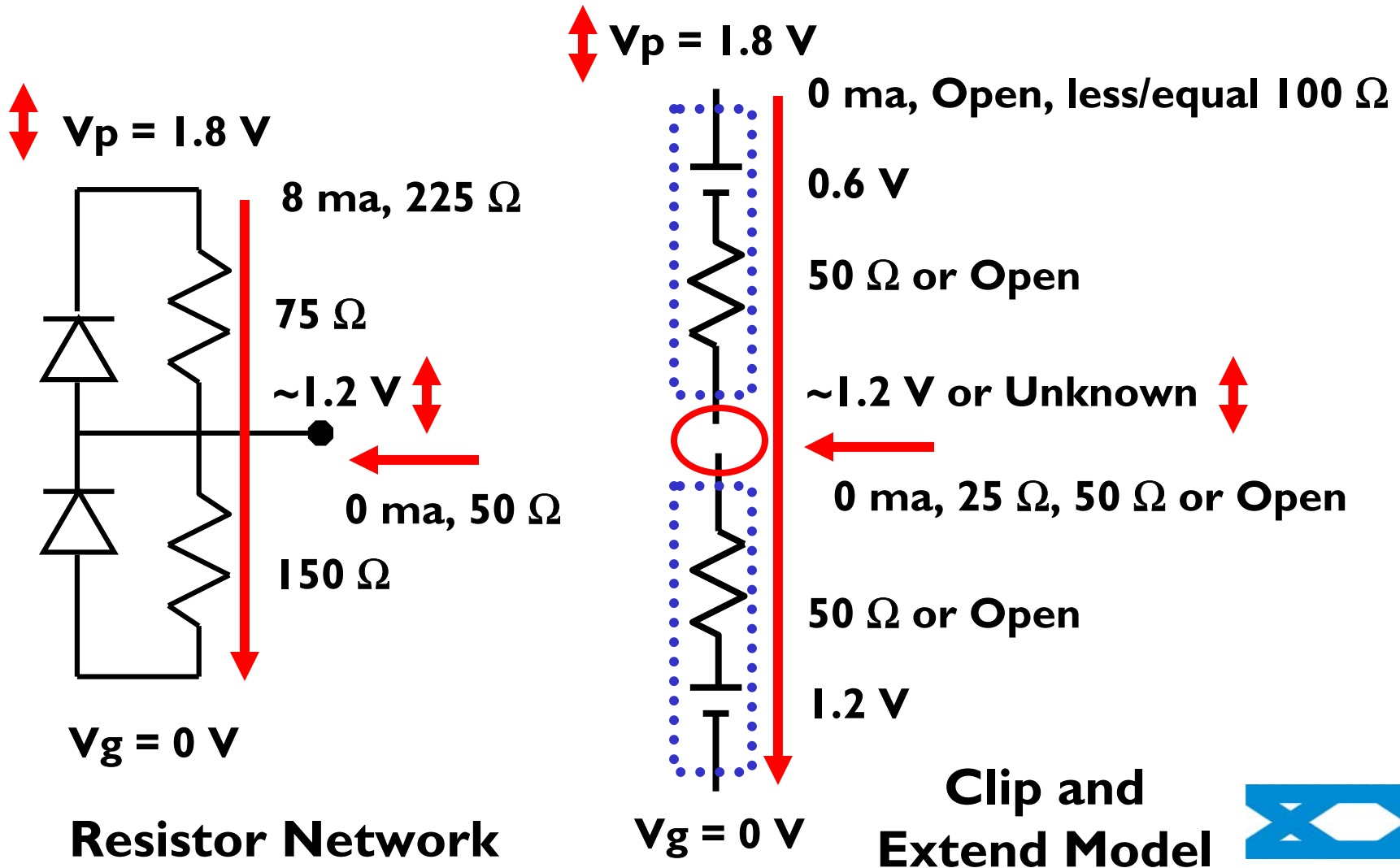
# Clip and Extend



**50  $\Omega$  Total I-V curve with 0.6 V  
“stick” diodes anchored to each rail**



# I(V) Blocks and Simulations



# Problems with Clip and Extend

- Wrong circuit impacting IBIS 3.2 and beyond
  - DC currents different (with, without I/O node circuit)
  - AC Thevenin impedances different and open
  - Higher frequency effects from non-linear elements
  - Driver at I/O node sees different impedance
- Tool dependencies including
  - Slope discontinuities issues
  - Open 0 ma discontinuities with potential simulation ambiguities and failures (Errors)
  - Unpredictable performance even with validation
- Avoid “Clip and Extend”, use DEC
- Be wary of any truncation recommendation



# DEC (from Resistors) Algorithm

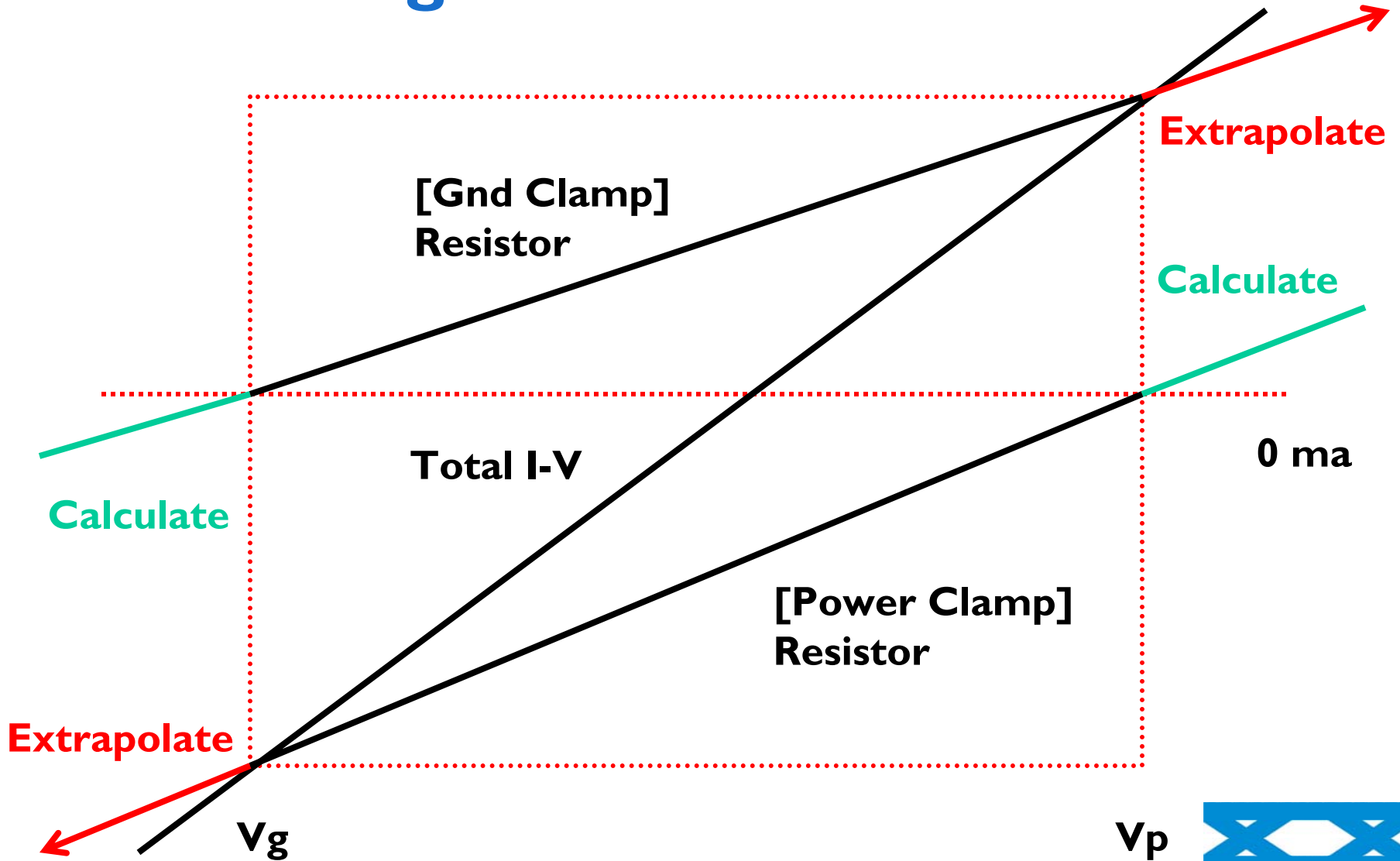
- Draw box bounded by  $(V_g, I_g)$  and  $(V_p, I_p)$  and draw the zero current axis
- Draw the three lower-left to upper right diagonals, where the upper region is for the [Gnd Clamp], and the lower region is for the [Power Clamp]
- **Deviate**: Proportionally allocate “Total I-V” delta deviation to [Gnd Clamp] and [Power Clamp] diagonals
- **Extrapolate** [Gnd Clamp] data ABOVE  $V_p$
- **Extrapolate** [Power Clamp] data BELOW  $V_g$
- **Calculate** [Gnd Clamp] data BELOW  $V_g$  (Total - PC)
- **Calculate** [Power Clamp] data ABOVE  $V_p$  (Total - GC)
- (Backup slides for some computational details)



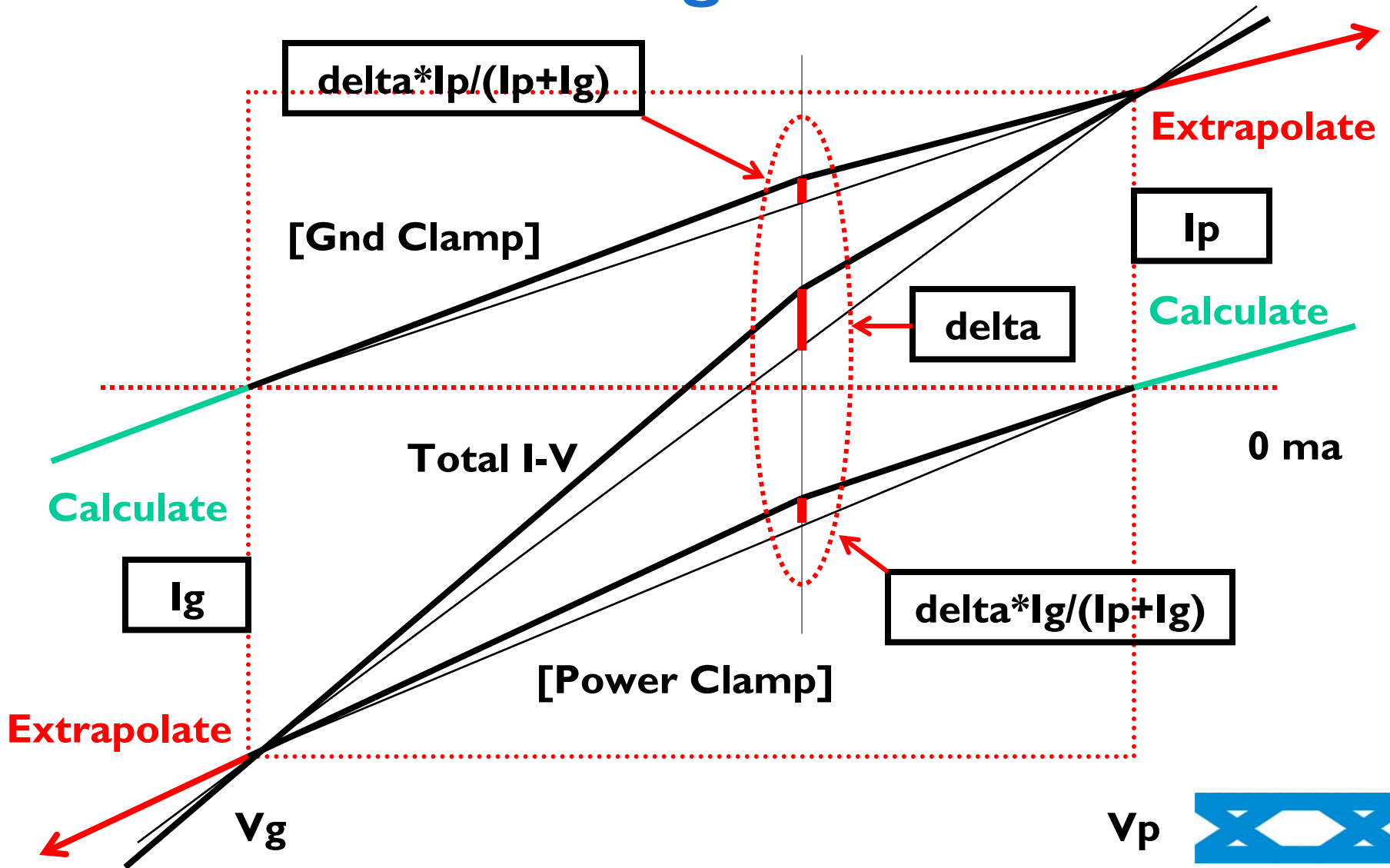
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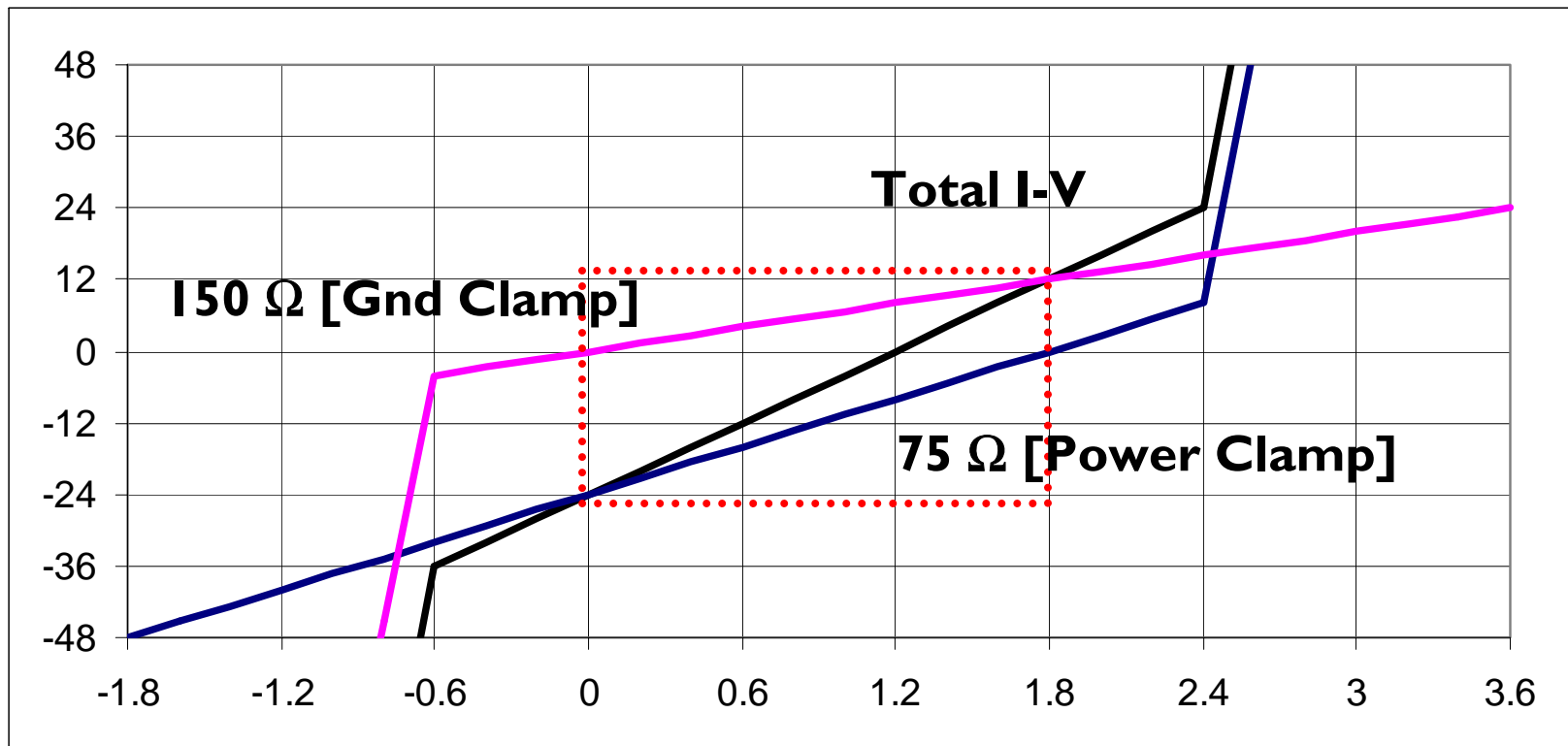
# Diagonals and Resistors



# DEC Algorithm



# ODT Example (delta=0)



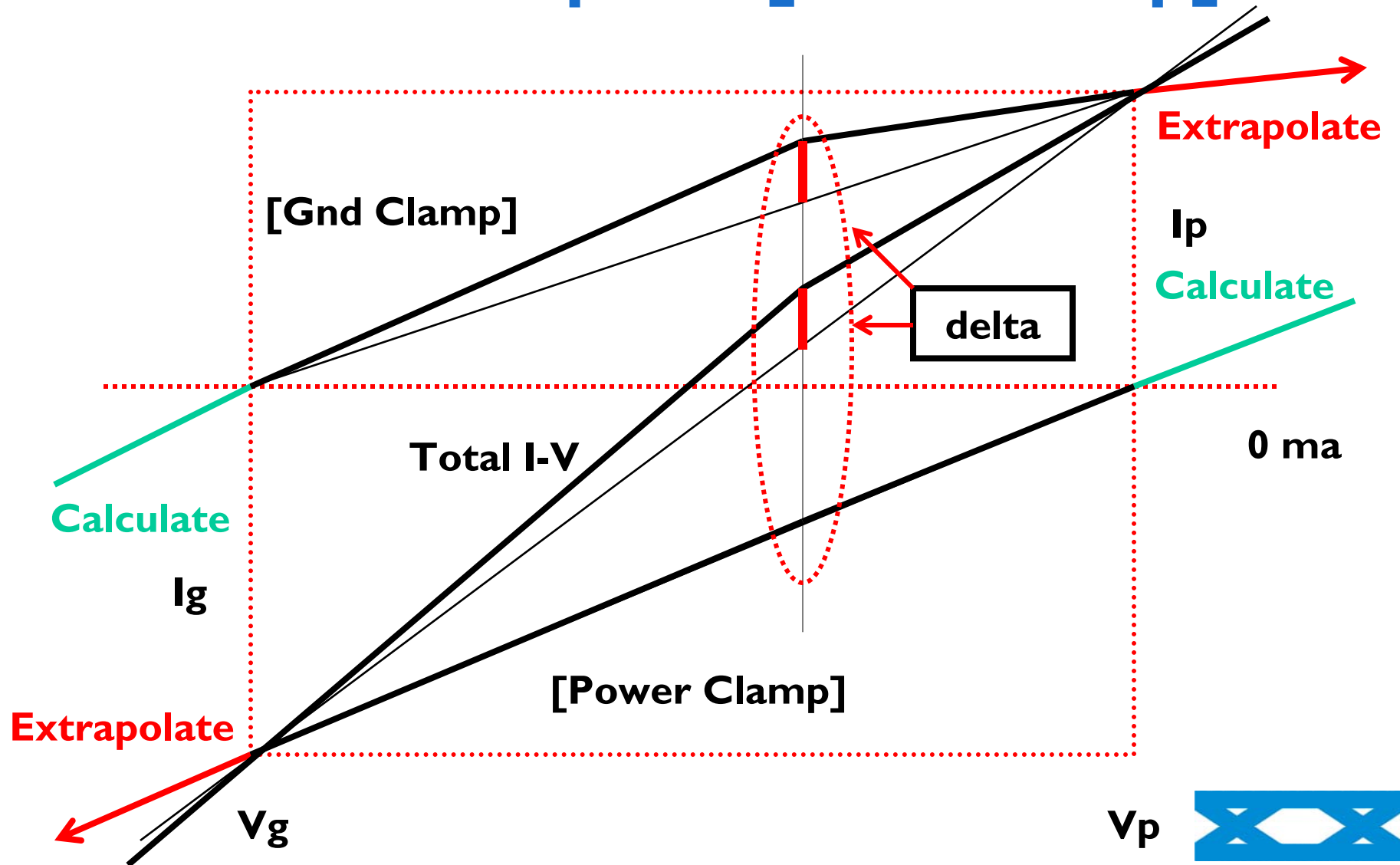
# DEC Observations

- Emulates ODT circuit for  $V_g$  and  $V_p$  changes
  - At I/O node, Thevenin 1.2 V shifts correctly, and source impedance = 50  $\Omega$
  - $V_p$  to  $V_g$  rail-to-rail impedance = 225  $\Omega$
  - Diodes correctly anchored to  $V_g$  and  $V_p$
- Supports single resistor ODT subsets
  - “pullup” ODT
  - “pulldown” ODT
- Backup slides for a suggested computation details
  - Typ-min-max data alignment
  - $V_{cc}$  relative [Power Clamp] calculation
- Shape anchoring and internal reference overrides next

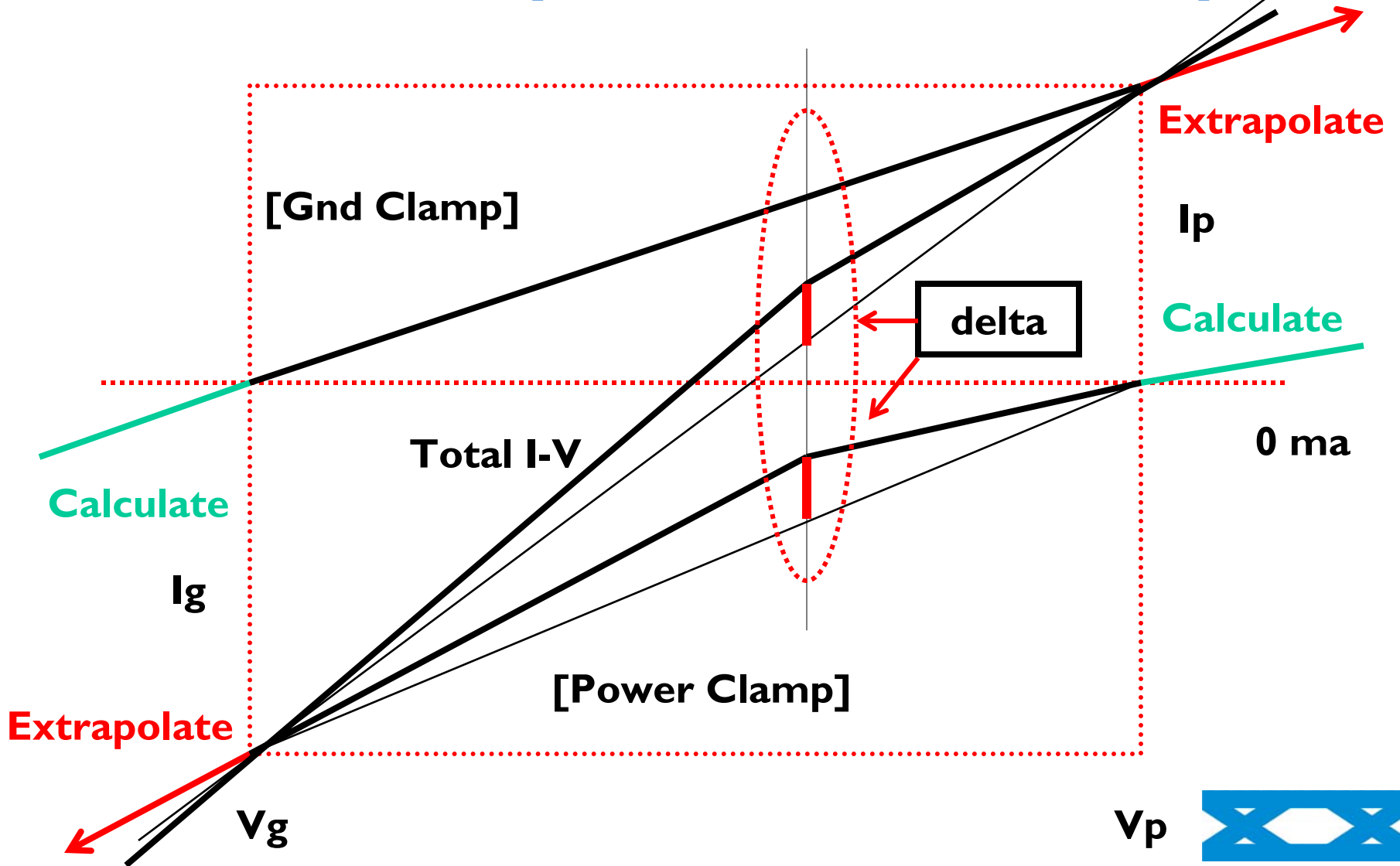


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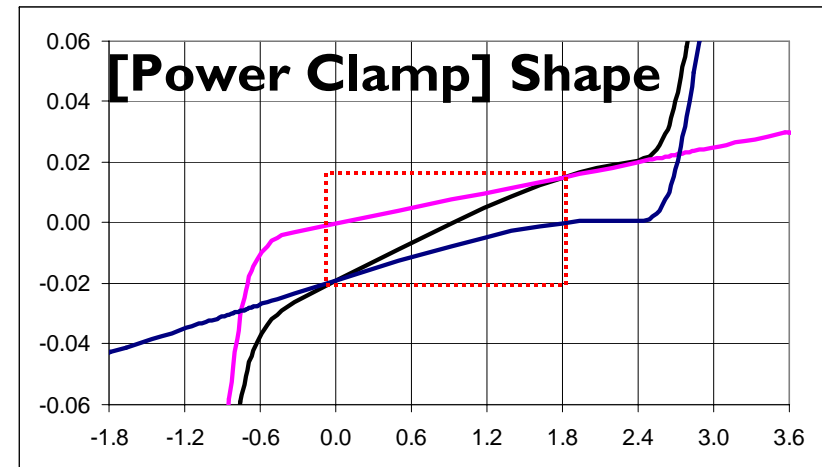
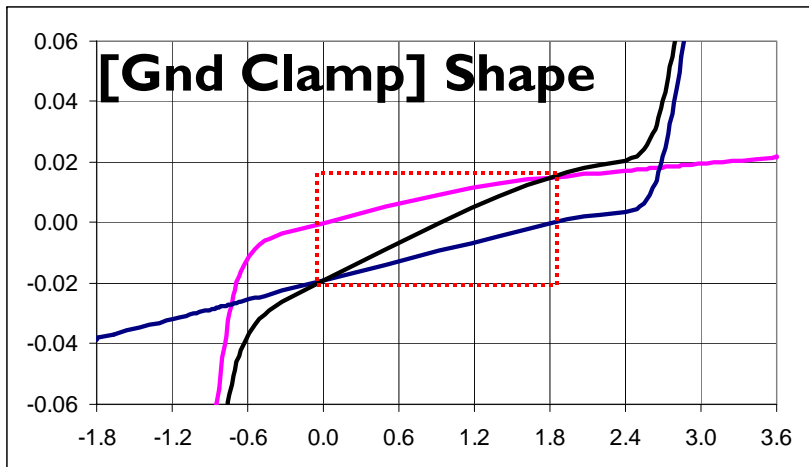
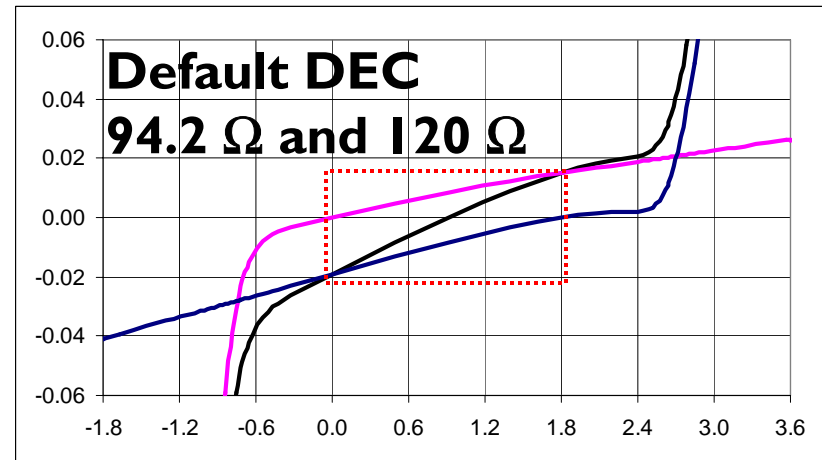
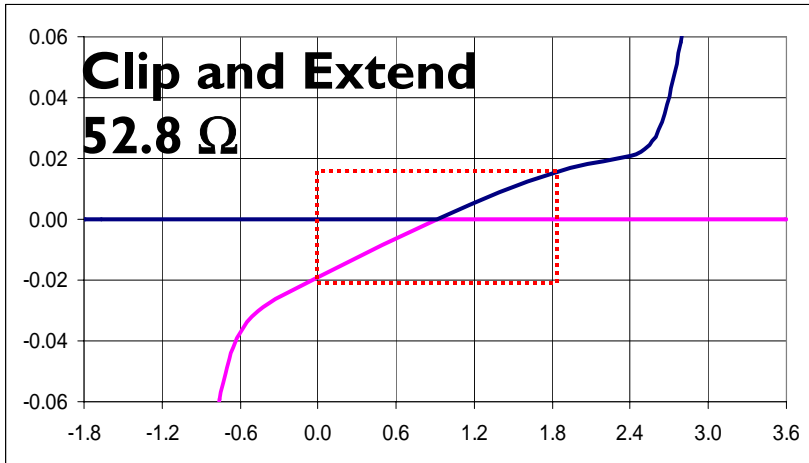
# Anchor Shape to [Gnd Clamp]



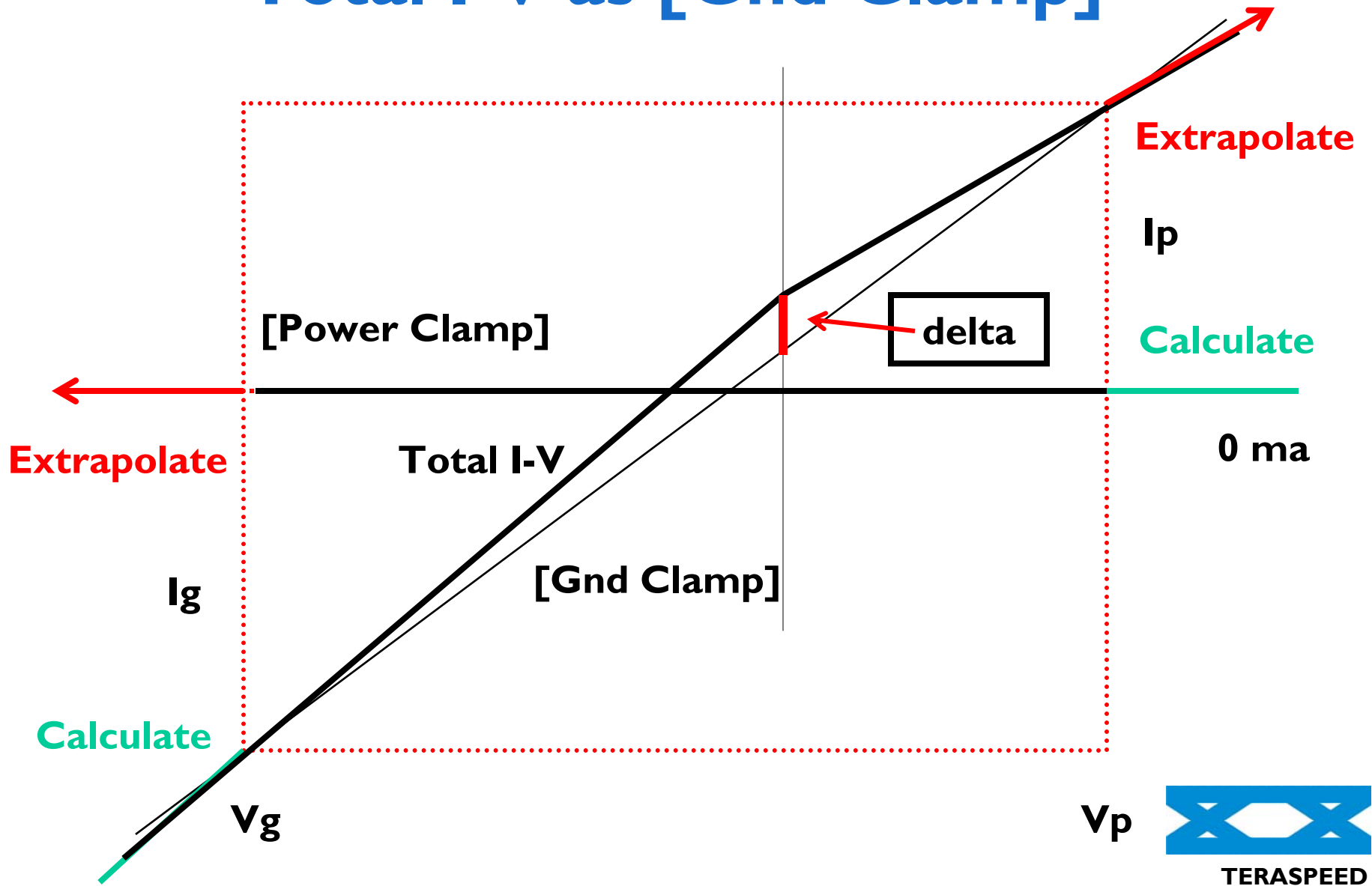
# Anchor Shape to [Power Clamp]



# Real “50 Ω” ODT Choices



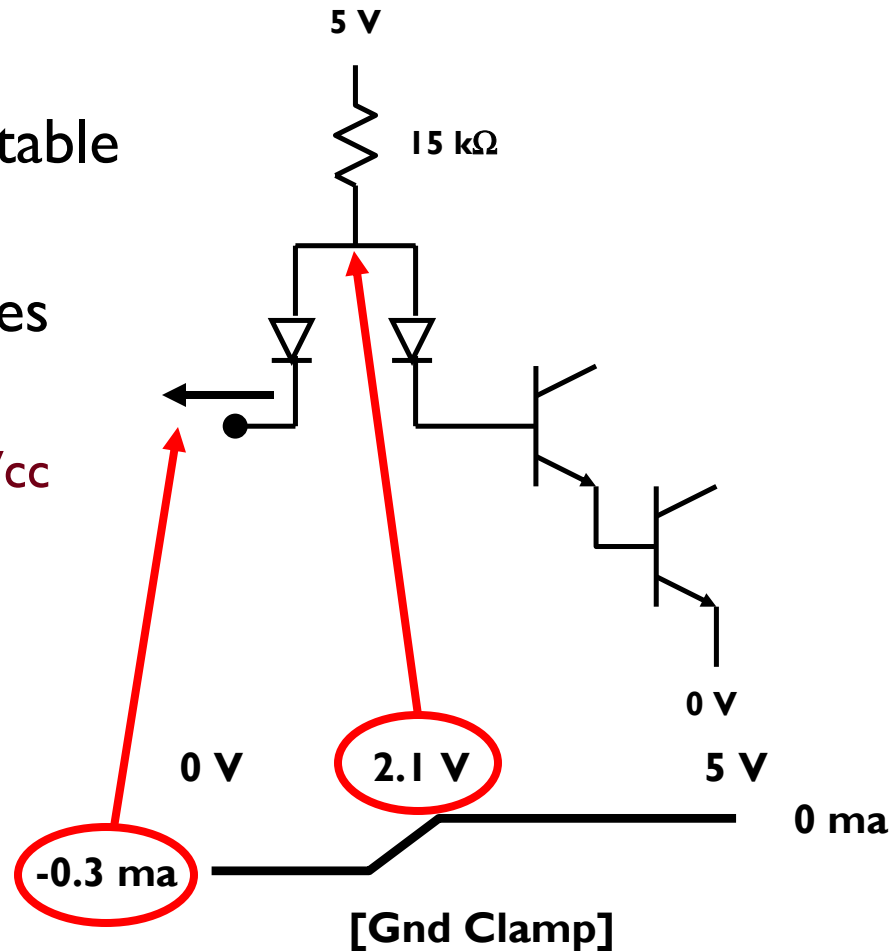
# Total I-V as [Gnd Clamp]





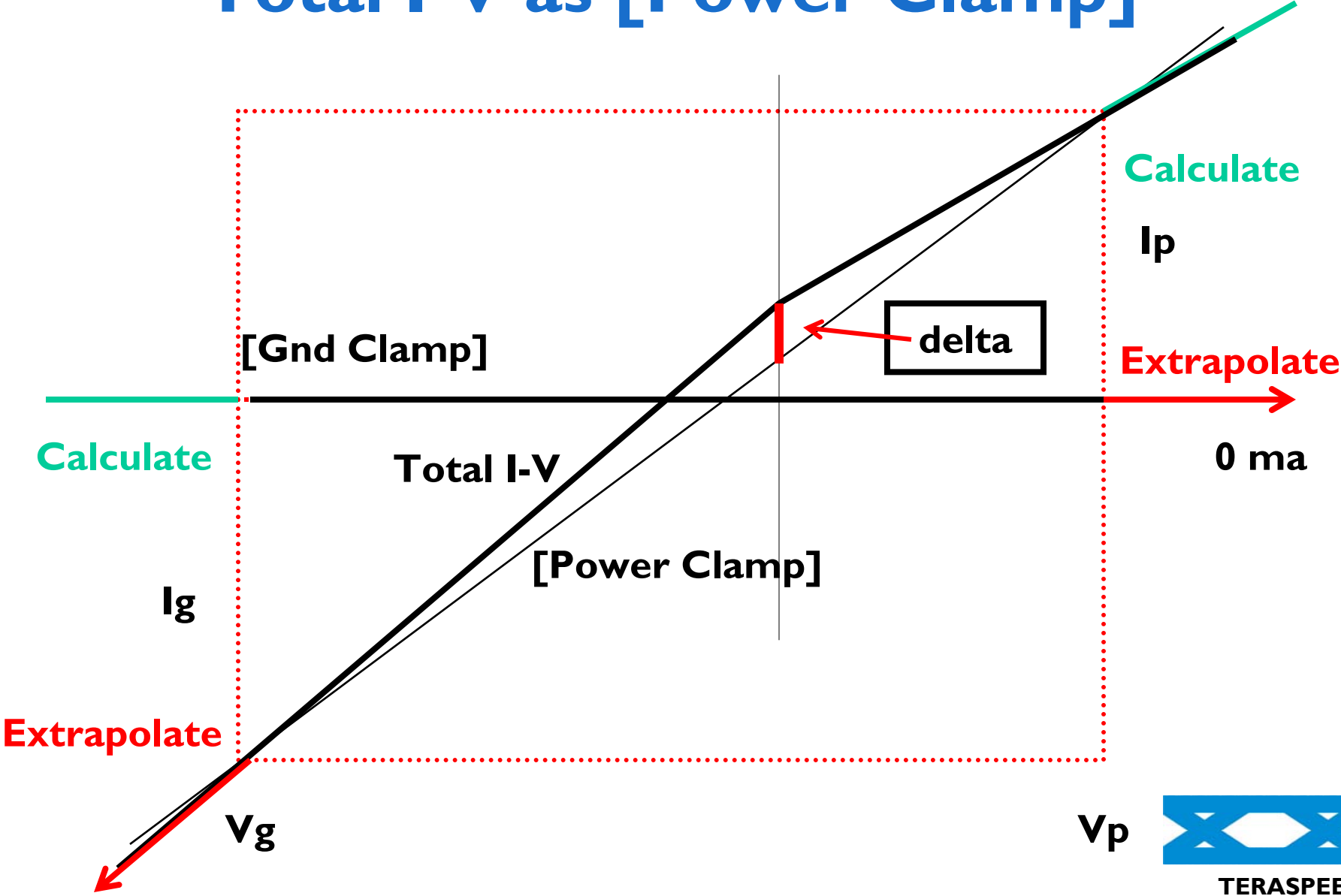
# Application

- Total I-V in [Gnd Clamp] table tracks  $V_g$  changes
- For legacy IBIS “clip” ranges
  - [Gnd Clamp]:  $-V_{cc}$  to  $V_{cc}$
  - [Power Clamp]:  $V_{cc}$  to  $2*V_{cc}$
- TTL Input: 2.1 V “diode” anchored to  $V_g$  per IBIS
- Current could have been anchored to  $V_p$  (default)
- Both anchors partially applicable

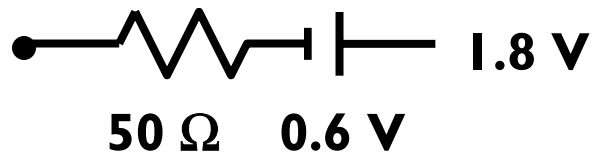
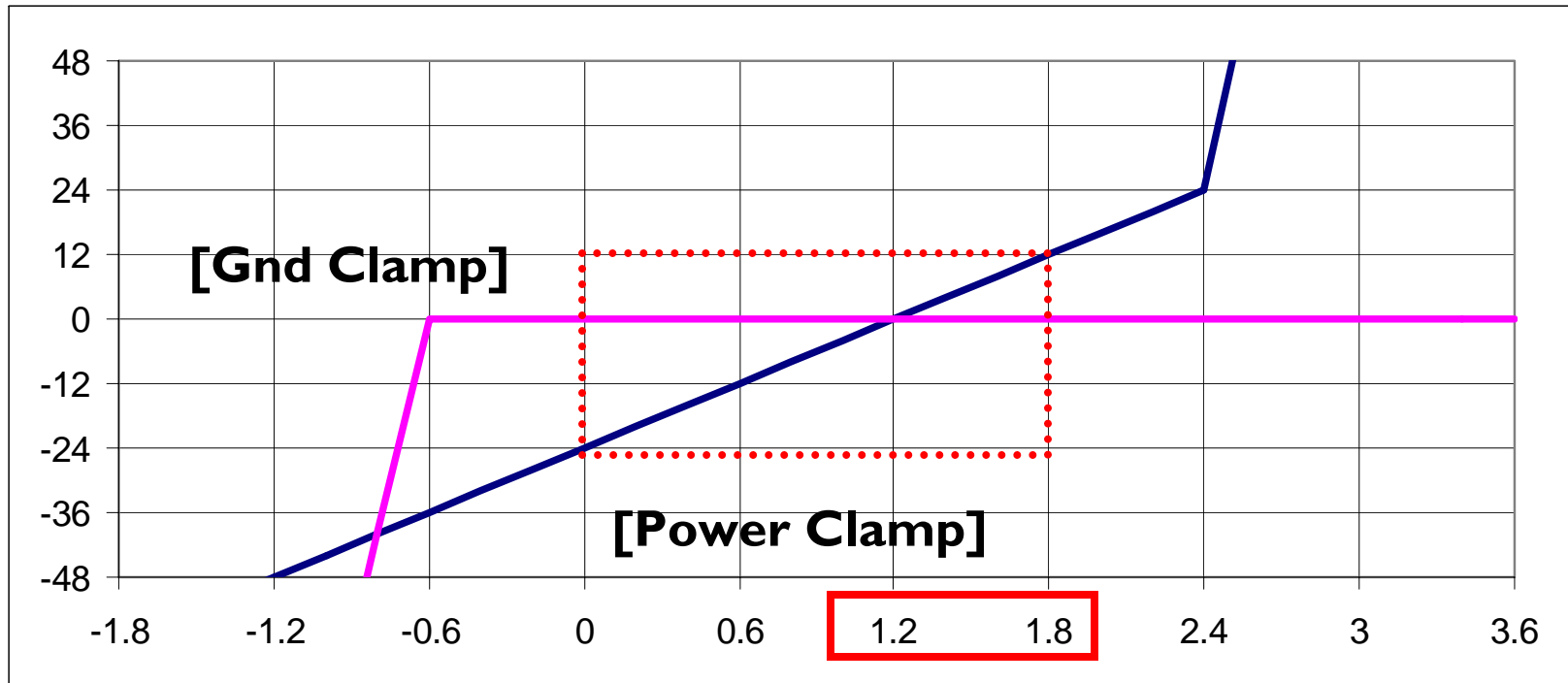




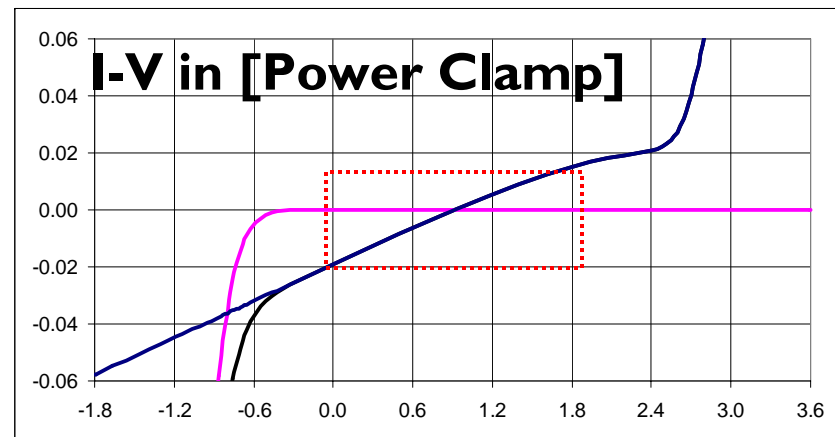
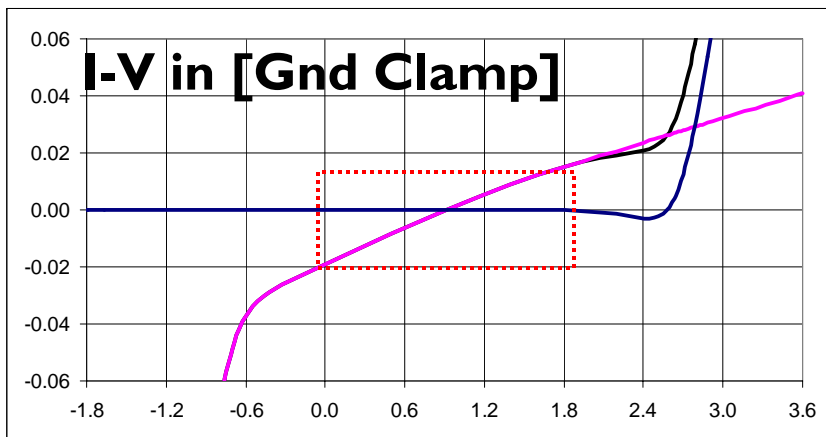
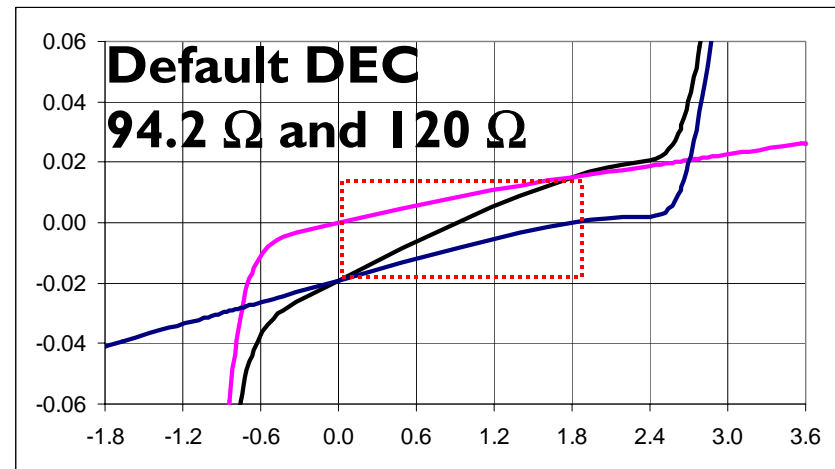
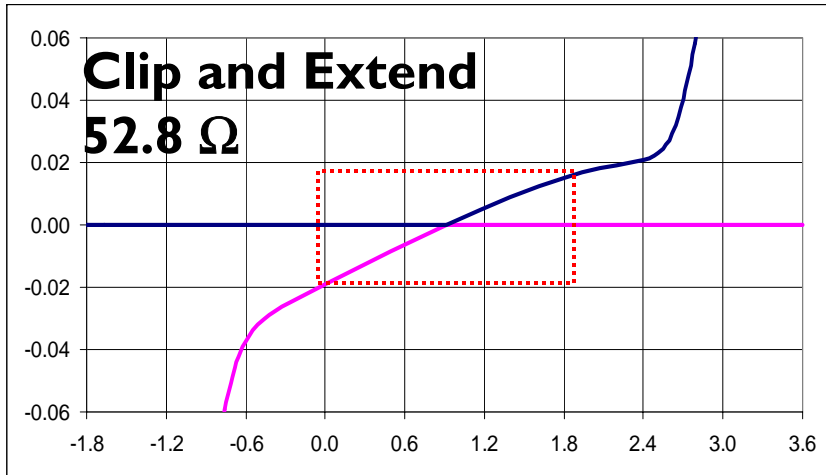
# Total I-V as [Power Clamp]



# 50 $\Omega$ , -0.6 V Anchored to Vp



# Real “50 Ω” ODT Choices

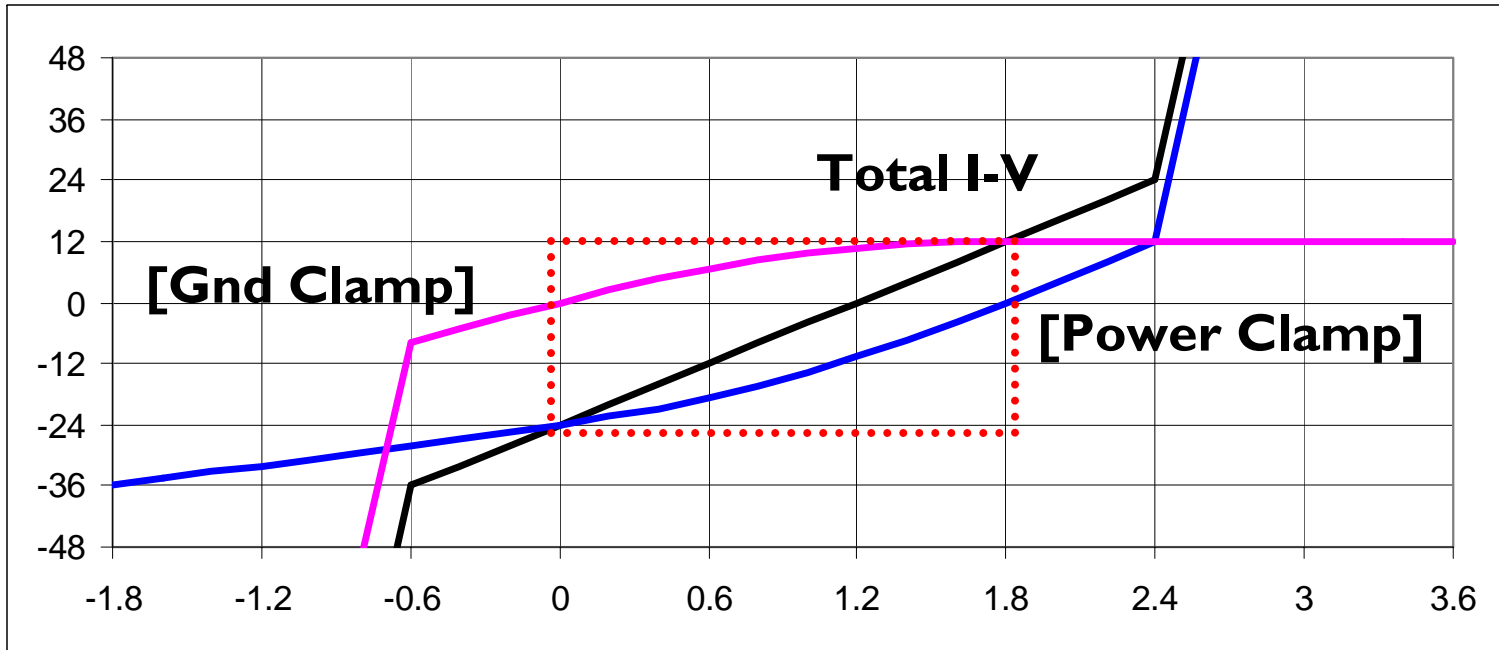


# Shape between $V_g$ and $V_p$

- In general Total I-V shape between  $V_g$  and  $V_p$  remains reasonable for  $V_g$  and  $V_p$  modulation
- DEC method applies for other reference shapes and other overrides
- Such as linear resistor partitioned into quadratic components next



# Quadratic Clamps



- Linear Thevenin terminator with “quadratic” resistors
  - [Gnd clamp] chosen with slope = 0 at  $V_p$
  - Use same Extrapolate and Calculate rules



# Conclusions

- Many choices exist to partition an I-V table into clamp tables
- DEC algorithm based on ODT resistor deviation covers practical cases
- Overrides shown, based on additional knowledge (could be expanded)
- DEC favored over “Clip and Extend” for accuracy, robustness, and portability



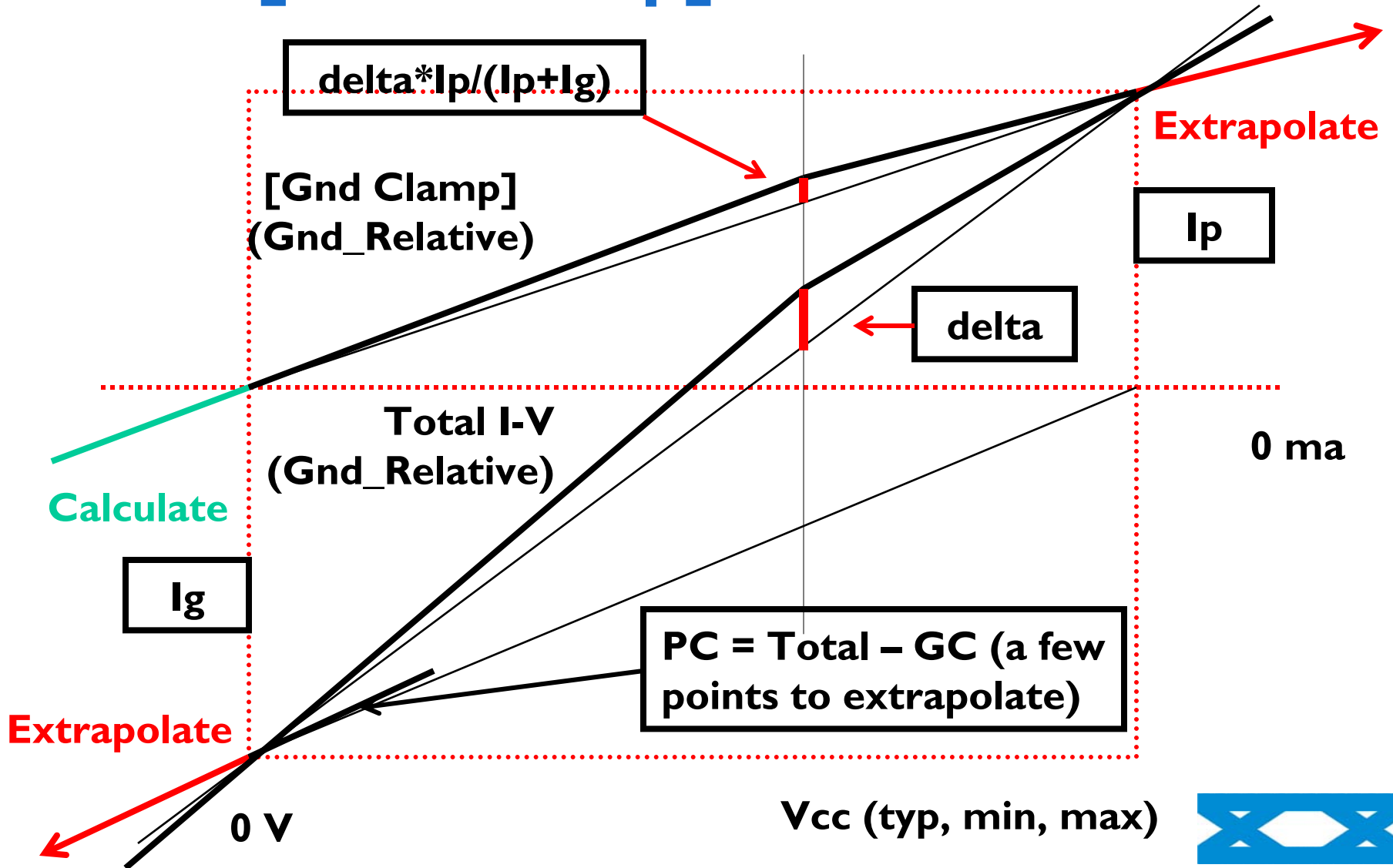


# Backup – Suggested Calculations

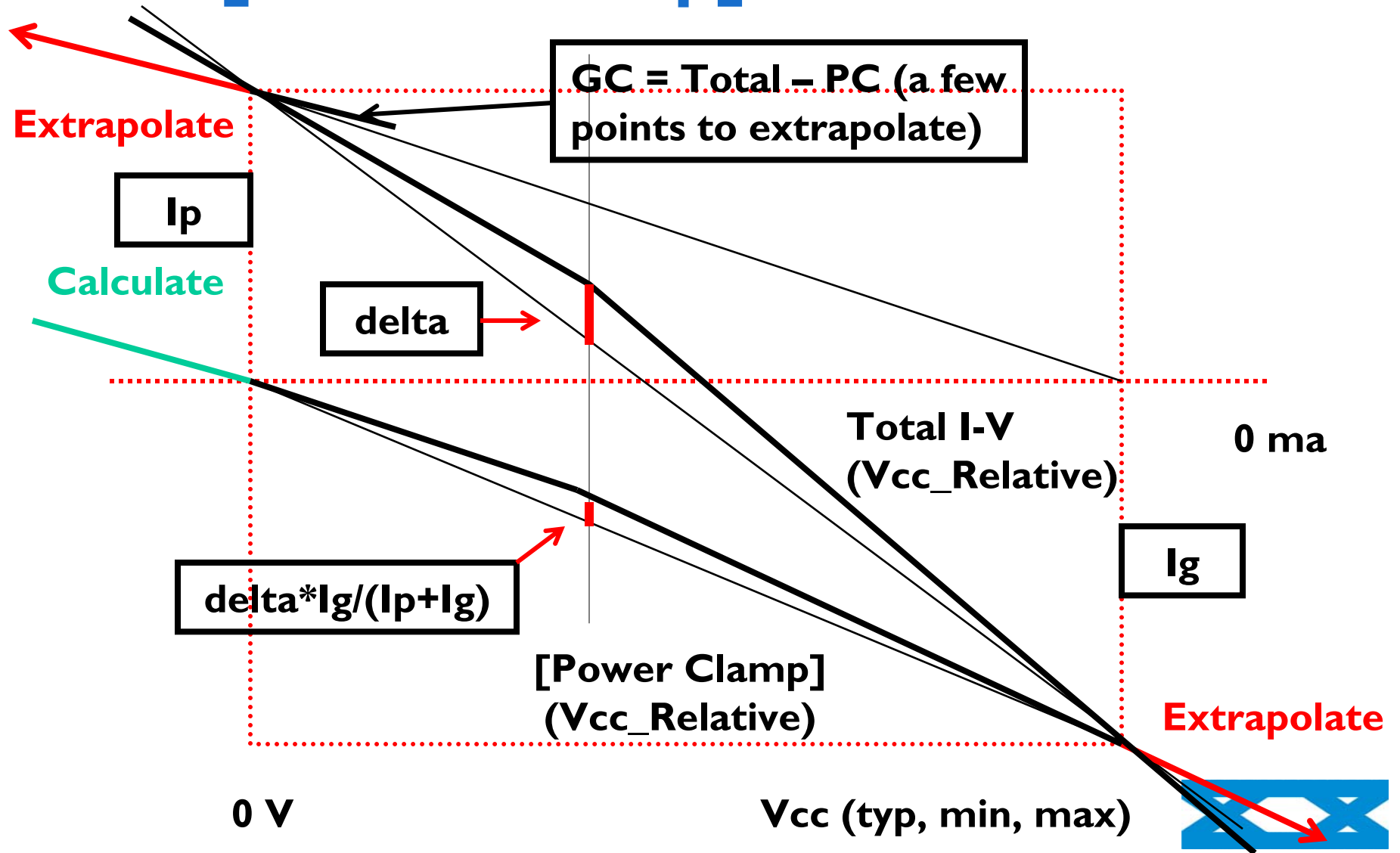
- Uses both a  $V_g$  (Gnd) referenced Total I-V and a  $V_p$  (typ, min, max  $V_{cc}$ ) referenced Total I-V
  - Typ, Min, Max for each case
    - From  $-V_{cc}$  to  $2*V_{cc}$
    - Same sample points aligned for typ, min, max data
  - [Gnd Clamp] uses  $V_g$  referenced data
  - [Power Clamp] uses  $V_p$  referenced data
  - (One Total I-V table could be calculated from the other over a larger sweep range to get aligned data)
- DEC – Extrapolate 0 to  $-V_{cc}$ , Calculate, do simple extrapolation above  $V_{cc}$  to  $2*V_{cc}$



# [Gnd Clamp] Calculation



# [Power Clamp] Calculation



# Comments

- Extrapolations below 0 V
  - Based on extrapolating a few calculated points
  - All data points at Total I-V voltages
- Extrapolate above  $V_{cc}$  (typ, min, max)
  - The typ and min columns need entries or NA's to  $V_{cc}$  (max)
  - Extrapolate columns to  $2*V_{cc}$ 
    - Fill in remaining values
    - Optionally, one value at  $2*V_{cc}$

